Notice of References Cited Application/Control No. 10/022,443 Examiner Feben M. Haile Applicant(s)/Patent Under Reexamination DUNN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0016684	01-2003	Prasad et al.	370/410
*	В	US-5,912,628	06-1999	Jeong, Ji-Woo	340/2.4
*	С	US-6,940,866	09-2005	Miller et al.	370/426
*	D	US-2002/0186702	12-2002	Ramos et al.	370/410
*	Е	US-2004/0081206	04-2004	Allison et al.	370/522
*	F	US-2001/0008532	07-2001	Lee, Seong Woo	370/467
	G	US-			
	Ι	US-			
	-	US-			
	٦	US-			
	K	US-			
	┙	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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	w							
	х							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.